

CY7C1020DV33

Features

- Pin-and function-compatible with CY7C1020CV33
- High speed
- t_{AA} = 10 ns
- · Low active power

— I_{CC} = 60 mA @ 10 ns

· Low CMOS standby power

 $-I_{SB2} = 3 \text{ mA}$

- · 2.0V Data retention
- Automatic power-down when deselected
- · CMOS for optimum speed/power
- · Independent control of upper and lower bits
- Available in Pb-free 44-pin 400-Mil wide Molded SOJ and 44-pin TSOP II packages

Functional Description^[1]

The CY7C1020DV33 is a high-performance CMOS static RAM organized as 32,768 words by 16 bits. This device has an automatic power-down feature that significantly reduces power consumption when deselected.

512K (32K x 16) Static RAM

<u>Writing</u> to the device is <u>accomplished</u> by taking Chip Enable (\overline{CE}) and Write Enable (WE) inputs LOW. If Byte Low Enable (BLE) is LOW, then data from I/O pins (I/O₀ through I/O₇), is written into the location specified <u>on the</u> address pins (A₀ through A₁₄). If Byte High Enable (BHE) is LOW, then data from I/O pins (I/O₈ through I/O₁₅) is written into the location specified on the address pins (A₀ through A₁₄).

Reading from the device is accomplished by taking Chip Enable (CE) and Output Enable (OE) LOW while forcing the Write Enable (WE) HIGH. If Byte Low Enable (BLE) is LOW, then data from the memory location specified by the address pins will appear on I/O_0 to I/O_7 . If Byte High Enable (BHE) is LOW, then data from memory will appear on I/O_8 to I/O_{15} . See the truth table at the back of this data sheet for a complete description of read and write modes.

The input/output pins (I/O₀ through I/O₁₅) are placed in <u>a</u> high-impedance state when the device is de<u>selected (CE</u> HIGH), the outputs are disabled (OE HIGH), the BHE and BLE are disable<u>d (BHE, BLE HIGH)</u>, or during a write operation (CE LOW, and WE LOW).

The CY7C1020DV33 is available in Pb-free 44-pin 400-Mil wide Molded SOJ and 44-pin TSOP II packages.



Notes

1. For guidelines on SRAM system design, please refer to the 'System Design Guidelines' Cypress application note, available on the internet at www.cypress.com

2. NC pins are not connected on the die.

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Selection Guide

| | –10 (Industrial) | –12 (Automotive) ^[3] | Unit |
|------------------------------|------------------|---------------------------------|------|
| Maximum Access Time | 10 | 12 | ns |
| Maximum Operating Current | 60 | 100 | mA |
| Maximum CMOS Standby Current | 3 | 15 | mA |

Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

| Storage Temperature65°C to +150°C |
|---|
| Ambient Temperature with Power Applied–55°C to +125°C |
| Supply Voltage on V_{CC} to Relative $GND^{[4]}$ –0.5V to +4.6V |
| DC Voltage Applied to Outputs in High-Z State ^[4] –0.5V to V _{CC} + 0.5V |
| in High-Z State ^[4] –0.5V to V _{CC} + 0.5V |
| DC Input Voltage ^[4] 0.5V to V _{CC} + 0.5V |

Electrical Characteristics Over the Operating Range

| Current into Outputs (LOW) | 20 mA |
|--|----------|
| Static Discharge Voltage (per MIL-STD-883, Method 3015) | > 2001V |
| Latch-up Current | > 200 mA |

Operating Range

| Range | Ambient Temperature | V _{cc} | Speed | |
|------------|------------------------|-----------------|-------|--|
| Industrial | -40 C to +85 C | $3.3V\pm0.3V$ | 10 ns | |
| Automotive | -40 C to +125 C | | 12 ns | |

| Devenueter | Description | Test Canditian | | –10 (Ir | dustrial) | -12 (Au | tomotive) | L lus i t |
|------------------|--|---|------------------|---------|-----------------------|---------|-----------------------|-----------|
| Parameter | Description | Test Conditions | | Min. | Max. | Min. | Max. | Unit |
| V _{OH} | Output HIGH Voltage | V _{CC} = Min., I _{OH} = -4.0 m | A | 2.4 | | 2.4 | | V |
| V _{OL} | Output LOW Voltage | V _{CC} = Min., I _{OL} = 8.0 mA | | | 0.4 | | 0.4 | V |
| V _{IH} | Input HIGH Voltage | | | 2.0 | V _{CC} + 0.3 | 2.0 | V _{CC} + 0.3 | V |
| V _{IL} | Input LOW Voltage ^[4] | | | -0.3 | 0.8 | -0.3 | 0.8 | V |
| I _{IX} | Input Load Current | $GND \leq V_I \leq V_{CC}$ | | -1 | +1 | -1 | +1 | μA |
| I _{OZ} | Output Leakage Current | $GND \leq V_{I} \leq V_{CC}$, Output | Disabled | -1 | +1 | -1 | +1 | μA |
| I _{CC} | V _{CC} Operating | V _{CC} = Max., | 100 MHz | | 60 | | - | mA |
| | Supply Current | $I_{OUT} = 0 \text{ mA},$ f = f _{MAX} = 1/t _{RC} | 83 MHz | | 55 | | 100 | mA |
| | | | 66 MHz | | 45 | | 90 | mA |
| | | | 40 MHz | | 30 | | 60 | mA |
| I _{SB1} | Automatic CE Power-down Current—TTL Inputs | Max. V _{CC} , <u>CE</u> ≥ V _{IH} V _{IN} ≥ V _{IH} or V _{IN} ≤ V _{IL} , f = | f _{MAX} | | 10 | | 50 | mA |
| I _{SB2} | Automatic CE Power-down Current—CMOS Inputs | $\begin{array}{l} \text{Max. } V_{\text{CC}}, \overline{\text{CE}} \geq V_{\text{CC}} - 0.\\ V_{\text{IN}} \geq V_{\text{CC}} - 0.3 \text{V, or } V_{\text{IN}} \leq \end{array}$ | | | 3 | | 15 | mA |

Notes

- 3. Automotive Product Information is Preliminary. 4. V_{IL} (min.) = -2.0V and V_{IH} (max) = V_{CC} + 1V for pulse durations of less than 5 ns.



Capacitance^[5]

| Parameter | Description | Test Conditions | Max. | Unit |
|------------------|--------------------|--|------|------|
| C _{IN} | Input Capacitance | T _A = 25°C, f = 1 MHz, V _{CC} = 3.3V | 8 | pF |
| C _{OUT} | Output Capacitance | | 8 | pF |

Thermal Resistance^[5]

| Parameter | Description | Description Test Conditions | | TSOP II | Unit | |
|-----------------|--|---|-------|---------|------|--|
| Θ_{JA} | | Still Air, soldered on a 3 × 4.5 inch, four-layer printed circuit board | 59.52 | 53.91 | °C/W | |
| Θ _{JC} | Thermal Resistance (Junction to Case) | | 36.75 | 21.24 | °C/W | |

AC Test Loads and Waveforms^[6]





Notes

 AC characteristics (except High-Z) are tested using the load conditions shown in Figure (a). High-Z characteristics are tested for all speeds using the test load shown in Figure (c).

^{5.} Tested initially and after any design or process changes that may affect these parameters.



Switching Characteristics Over the Operating Range ^[7]

| Deveneter | Description | –10 (Inc | lustrial) | –12 (Aut | 11 | |
|-----------------------------------|---|----------|-----------|----------|------|------|
| Parameter | Description | Min. | Max. | Min. | Max. | Unit |
| Read Cycle | - | | | | | _ |
| t _{power} ^[8] | V _{CC} (typical) to the first access | 100 | | 100 | | μs |
| t _{RC} | Read Cycle Time | 10 | | 12 | | ns |
| t _{AA} | Address to Data Valid | | 10 | | 12 | ns |
| t _{OHA} | Data Hold from Address Change | 3 | | 3 | | ns |
| t _{ACE} | CE LOW to Data Valid | | 10 | | 12 | ns |
| t _{DOE} | OE LOW to Data Valid | | 5 | | 6 | ns |
| t _{LZOE} | OE LOW to Low-Z ^[9] | 0 | | 0 | | ns |
| t _{HZOE} | OE HIGH to High-Z ^[9, 10] | | 5 | | 6 | ns |
| t _{LZCE} | CE LOW to Low-Z ^[9] | 3 | | 3 | | ns |
| t _{HZCE} | CE HIGH to High-Z ^[9, 10] | | 5 | | 6 | ns |
| t _{PU} ^[11] | CE LOW to Power-up | 0 | | 0 | | ns |
| t _{PD} ^[11] | CE HIGH to Power-down | | 10 | | 12 | ns |
| t _{DBE} | Byte Enable to Data Valid | | 5 | | 6 | ns |
| t _{LZBE} | Byte Enable to Low-Z | 0 | | 0 | | ns |
| t _{HZBE} | Byte Disable to High-Z | | 5 | | 6 | ns |
| Write Cycle ^{[12} | 2] | | | | | - |
| t _{WC} | Write Cycle Time | 10 | | 12 | | ns |
| t _{SCE} | CE LOW to Write End | 8 | | 9 | | ns |
| t _{AW} | Address Set-up to Write End | 8 | | 9 | | ns |
| t _{HA} | Address Hold from Write End | 0 | | 0 | | ns |
| t _{SA} | Address Set-up to Write Start | 0 | | 0 | | ns |
| t _{PWE} | WE Pulse Width | 7 | | 8 | | ns |
| t _{SD} | Data Set-up to Write End | 5 | | 6 | | ns |
| t _{HD} | Data Hold from Write End | 0 | | 0 | | ns |
| t _{LZWE} | WE HIGH to Low-Z ^[9] | 3 | | 3 | | ns |
| t _{HZWE} | WE LOW to High-Z ^[9, 10] | | 5 | | 6 | ns |
| t _{BW} | Byte Enable to End of Write | 7 | | 8 | | ns |

Notes

Notes
7. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V.
8. t_{POWER} gives the minimum amount of time that the power supply should be at typical V_{CC} values until the first memory access can be performed
9. t_{HZDE}, t_{HZDE}, t_{HZDE}, and t_{HZWE} are specified with a load capacitance of 5 pF as in (c) of AC Test Loads. Transition is measured when the outputs enter a high impedance state.
10. At any given temperature and voltage condition, t_{HZCE} is less than t_{LZCE}, t_{HZDE} is less than t_{LZDE}, and t_{HZWE} for any given device.
11. This parameter is guaranteed by design and is not tested.
12. The internal Write time of the memory is defined by the overlap of CE LOW, WE LOW and BHE/BLE LOW. CE, WE and BHE/BLE must be LOW to initiate a Write and the transition of these signals can terminate the Write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the Write.



Data Retention Characteristics (Over the Operating Range)

| Parameter | Description | Conditions | | Min. | Max. | Unit |
|---------------------------------|--------------------------------------|--|------------|-----------------|------|------|
| V _{DR} | V _{CC} | | | 2.0 | | V |
| I _{CCDR} | Data Retention Current | $V_{CC} = V_{DR} = 2.0V, \overline{CE} \ge V_{CC} - 0.3V,$ $V_{IN} \ge V_{CC} - 0.3V \text{ or } V_{IN} \le 0.3V$ | Industrial | | 3 | mA |
| | | $V_{\text{IN}} \ge V_{\text{CC}} - 0.3V \text{ or } V_{\text{IN}} \le 0.3V$ | Automotive | | 15 | mA |
| t _{CDR} ^[5] | Chip Deselect to Data Retention Time | | | 0 | | ns |
| t _R ^[13] | Operation Recovery Time | | | t _{RC} | | ns |

Data Retention Waveform



Switching Waveforms

Read Cycle No. 1 (Address Transition Controlled)^[14, 15]





Read Cycle No. 2 (OE Controlled)^[15, 16]

Notes:

13. Full device operation requires linear V_{CC} ramp from V_{DR} to $V_{CC(min.)} \ge 50 \,\mu s$ or stable at $V_{CC(min.)} \ge 50 \,\mu s$. 14. <u>Device</u> is continuously selected. OE, CE, BHE and/or BLE = V_{IL} . 15. WE is HIGH for Read cycle.

16. Address valid prior to or coincident with \overline{CE} transition LOW.



Switching Waveforms (continued)

Write Cycle No. 1 (CE Controlled)^[17, 18]



Write Cycle No. 2 (BLE or BHE Controlled)



Notes:

17. Data I/O is high impedance if \overline{OE} or \overline{BHE} and/or $\overline{BLE} = V_{IH}$. 18. If \overline{CE} goes HIGH simultaneously with \overline{WE} going HIGH, the output remains in a high-impedance state.



Switching Waveforms (continued)





Truth Table

| CE | OE | WE | BLE | BHE | I/O ₀ –I/O ₇ | I/O ₈ –I/O ₁₅ | Mode | Power |
|----|----|----|-----|-----|------------------------------------|-------------------------------------|----------------------------|----------------------------|
| Н | Х | Х | Х | Х | High-Z | High-Z | Power-down | Standby (I _{SB}) |
| L | L | Н | L | L | Data Out | Data Out | Read—All bits | Active (I _{CC}) |
| | | | L | Н | Data Out | High-Z | Read—Lower bits only | Active (I _{CC}) |
| | | | Н | L | High-Z | Data Out | Read—Upper bits only | Active (I _{CC}) |
| L | Х | L | L | L | Data In | Data In | Write—All bits | Active (I _{CC}) |
| | | | L | Н | Data In | High-Z | Write—Lower bits only | Active (I _{CC}) |
| | | | Н | L | High-Z | Data In | Write—Upper bits only | Active (I _{CC}) |
| L | Н | Н | Х | Х | High-Z | High-Z | Selected, Outputs Disabled | Active (I _{CC}) |
| L | Х | Х | Н | Н | High-Z | High-Z | Selected, Outputs Disabled | Active (I _{CC}) |



Ordering Information

| Speed (ns) | Ordering Code | Package Name | Package Type | Operating Range |
|---------------|---------------------|-----------------|---------------------------------------|-----------------|
| 10 | CY7C1020DV33-10VXI | 51-85082 | 44-pin (400-Mil) Molded SOJ (Pb-free) | Industrial |
| | CY7C1020DV33-10ZSXI | 51-85087 | 44-pin TSOP Type II (Pb-free) | |
| 12 | CY7C1020DV33-12ZSXE | 51-85087 | 44-pin TSOP Type II (Pb-free) | Automotive |

Ordering Code Definitions



Shaded areas contain advance information. Please contact your local Cypress sales representative for availability of these parts.



Package Diagrams





51-85082 *C



Package Diagrams (continued)





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Document History Page

Document Title: CY7C1020DV33, 512K (32K x 16) Static RAM Document Number: 38-05461

| REV. | ECN NO. | Issue Date | Orig. of Change | Description of Change |
|------|---------|------------|--------------------|--|
| ** | 201560 | See ECN | SWI | Advance Information data sheet for C9 IPP |
| *A | 233695 | See ECN | RKF | DC parameters modified as per EROS (Spec # 01-02165) Pb-free Offering in Ordering Information |
| *B | 262950 | See ECN | RKF | Changed I/O ₁ – I/O ₁₆ to I/O ₀ – I/O ₁₅ Added Data Retention Characteristics table Added T _{power} spec in Switching Characteristics table Added 44-SOJ package diagram Shaded Ordering Information |
| *C | 307596 | See ECN | RKF | Reduced Speed bins to -8 and -10 ns |
| *D | 560995 | See ECN | VKN | Converted from Preliminary to Final Removed Commercial operating range Removed 8 ns speed bin Added Automotive information Added I_{CC} values for the frequencies 83MHz, 66MHz and 40MHz Updated Thermal Resistance table Updated Ordering Information table Changed Overshoot spec from V_{CC} +2V to V_{CC} +1V in footnote #4 |
| *E | 2898399 | 03/24/2010 | AJU | Updated Package Diagrams |
| *F | 3109992 | 12/14/2010 | AJU | Added Ordering Code Definitions. |



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